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Amendments to the Abstract:

Please amend the Abstract as follows:

When using a rigid substrate eddy current probe to measure a non-planer test piece, the probe must be adapted to the test piece shape in order to avoid incorrect measurement values.

Disclosed is a probe which is configured in a flexible manner ~~by means of~~ via a flexible substrate so as to be adjustable to different radii of curvature of a test piece. Furthermore the ~~The probe~~ lining is also embodied in an elastic manner.--

A clean copy of the Abstract that incorporates the above amendments is provided herewith on a separate page.